

| Simulation Parameter / Observable / Task (*) directly observable in experiments. | Methodology Used | Example Material / Type (if applicable) | Notes / Example references |
|---|--|--|--|
| Decomposition and binding / chemisorption mechanisms/mode (kinetics and thermodynamics) | DFT/HF/post-HF/ML + kMC+ MD Hybrid ONIOM method, CCSD(T), MP2, B3LYP & HF/6-31G(d,p) Climbing image-(CI)-NEB, RMD simulations using LAMMPS | Various ALD (mainly Al ₂ O ₃) + TiO ₂ + Cu(acac) ₂ , Ti(CpMe ₅) + ZrO ₂ | 76 , 169 , 75 , 131 , 77 , 80 , 171 |
| Growth rate*, and temperature dependence (kinetics) of growth rate*; based on chemisorption process | DFT + kMC+ MD CFD Mass balance; LBM Monte Carlo | TiO ₂ ALD Various ALD Zinc Oxide | 73 , 78 , 83 , 93 , 96 , 157 , 158 , 159 , 160 , 161 , 162 , 163 , 164 , 165 , 97 , 95 |
| Surface desorption, diffusion and reaction rates | Mainly DFT + kMC + MD | Various ALD/ALE | Also involves reading from tables |
| Binding affinity and sticking coefficients of adsorbate (precursor/etchant/inhibitor) | mainly DFT + kMC and MD Potential extension to ML Empirical and numerical (ANSYS) | HfO ₂ ALD, Pt precursors on graphene | 70 , 74 , 79 , 100 , 162 , 166 , 167 , 168 , 148 , 147 |
| Film (materials) properties: uniformity, roughness, density, temperature profile (thermal conduction), chemical composition (element analysis)* | CFD and numerical, Mass balance | | |
| Designing (/screening) new ALD precursors, ALE etchants or AS inhibitors (SMLs, SAMs) | DFT and ML (combined with structure prediction) only | Silicon and Carbon precursors | 178 |
| Predict cation ratios in ternary oxides (elemental analysis) | Mass balance; LBM Monte Carlo | | |
| Carrier gas flow and temperature profile | GCM/CAMD; CFD; MC Mass balance | HfO ₂ ALD, Alumina | 70 , 74 , 79 , 100 , 162 , 166 , 167 , 168 , 149 |
| Modelling the morphology evolution | Mass balance; LBM Monte Carlo | | 56 , 66 , 86 , 94 , 179 , 180 |
| Modelling the precursor exposure on 3D substrates | Continuum Fluid Dynamics (CFD) and ANSYS | | 56 , 66 , 86 , 94 , 179 , 180 |
| Surface coverage by the adsorbate Surface coverage as a function of time or rotation speed (spatial ALE of Al ₂ O ₃) | DFT+kMC Continuum Fluid Dynamics (CFD) | Various ALD/ALE | Coatings 2023 , 13 , 558v Reactor-scale |

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|---|---|---|---|
| Design and operation variables, e.g. the gap distance, purge and precursor gas flow rates, substrate velocity, and vacuum pressure have on the substrate film etching per cycle and uniformity. | Continuum Fluid Dynamics (CFD) | spatial ALE of Al ₂ O ₃ | Coatings 2023, 13, 558v |
| Precursor pressure inside the reactor Simulated quartz crystal microbalance (QCM) and quadrupole mass spectrometry (QMS) plots | Continuum Fluid Dynamics (CFD) | TiO ₂ ALD from titanium tetraisopropoxide and titanium tetrachloride precursors. | Reactor-scale |
| Growing of nanoclusters | DFT, QM/MM calculations using ONIOM implementation (DFT and classical MM) | Copper oxide nanoclusters on porphyrin | 175 |

* directly observable in experiments.

Key parameters / observables and reference methodology*

Atomistic (nano-mesoscale)

- Energy barrier (kinetics), and reaction energies (thermodynamics) (DFT and kMC)
- Sticking coefficient, surface coverage and binding affinity
- etc.

Continuum (meso-macroscale)

- Surface coverage (CFD)
- Film uniformity, roughness, density, temperature profile (thermal conduction), chemical composition

* directly observable in experiments.

Glossary: Continuum Fluid Dynamics CFD; Group Contribution Method GCM; Computer-Aided Molecular Design CAMD; The Lattice Boltzmann Method LBM; (Kinetic) Monte Carlo kMC/MC; Hartree-Fock HF

References

A comprehensive overview and relevant studies can be found in [Nanomaterials 2022, 12, 831](#) (See Table 2)

Also see [Coatings 2023, 13, 558](#)

[Review of atomic layer deposition process, application and modeling tools - ScienceDirect](#)

[Reactor scale simulations of ALD and ALE: Ideal and non-ideal self-limited processes in a cylindrical and a 300 mm wafer cross-flow reactor | Journal of Vacuum Science & Technology A | AIP Publishing](#)